

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/802,529	BACHINSKI ET AL.
Examiner	Art Unit	
Jinhee J. Lee	2831	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
174	as above	5/31/2005	LEE
439	as above	5/31/2005	LEE